

<b>Notice of References Cited</b>	Application/Control No. 10/718,208	Applicant(s)/Patent Under Reexamination NAGANATHAN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0016944	02-2002	Yoshida et al.	714/758
	B	US-			
	C	US-			
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